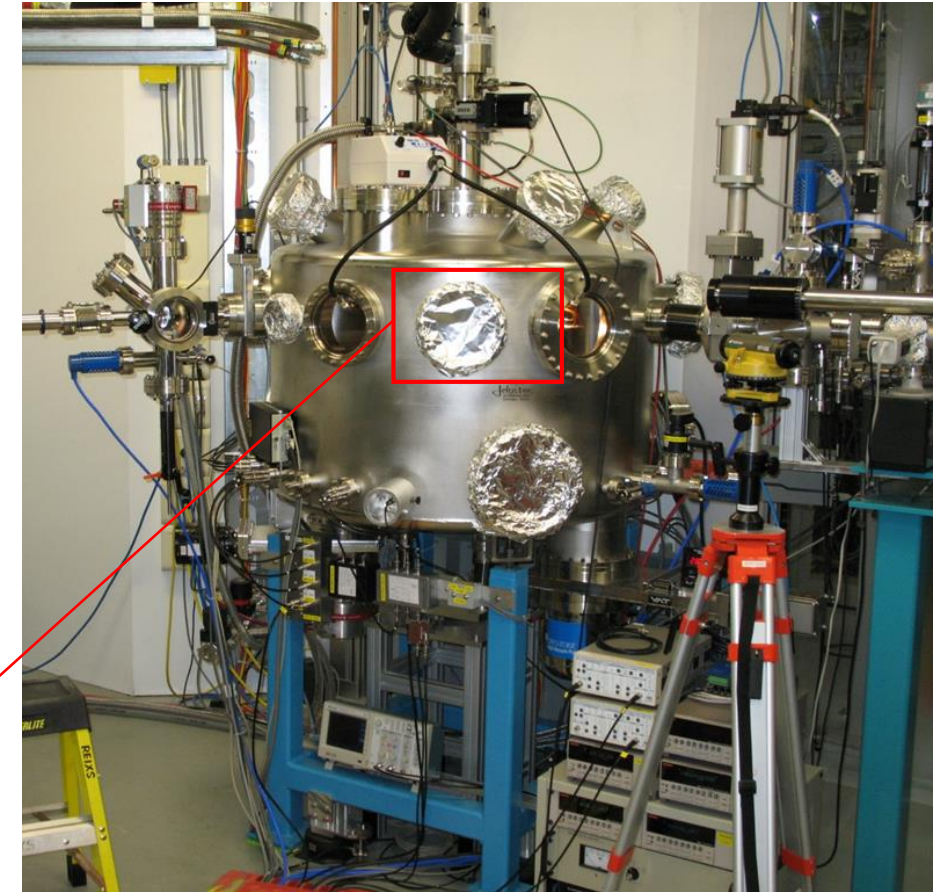


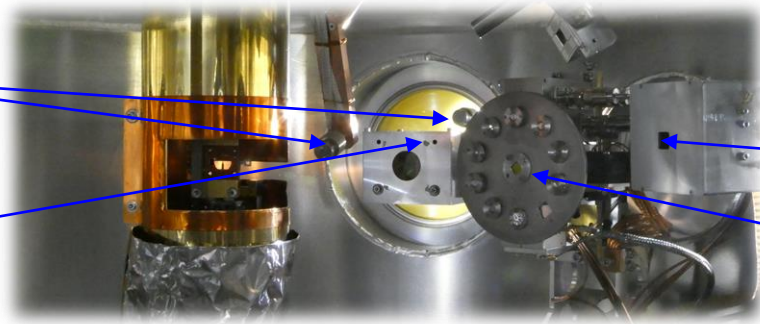
# Resonant X-ray Scattering Endstation (RSXS)

<b>Vacuum</b>	$\approx 5 \times 10^{-10}$ Torr
<b>Sample Stage</b>	Four-circle Diffractometer
<b>Sample Temperature</b>	20 – 380 K
<b>Detectors</b>	<ul style="list-style-type: none"><li>- Primary Silicon Drift Detector: 250 – 2500 eV</li><li>- Secondary Silicon Drift Detector: 250 – 2500 eV</li><li>- Micro-channel Plate w/ position readout (100um)</li><li>- Filter/Slit Wheel with Photodiode or CEM</li><li>- Polarization Analyzer (4 multi-layers)</li></ul>
<b>Sample Environment</b>	<ul style="list-style-type: none"><li>- Static Magnetic Field</li><li>- Sample Bias (<math>\pm 500</math>V)</li></ul>
<b>Techniques</b>	<ul style="list-style-type: none"><li>- Resonant Soft X-ray Scattering (RSXS)</li><li>- Resonant X-ray Reflectivity (RXR)</li><li>- X-ray Absorption Spectroscopy (XAS)</li><li>- X-ray Magnetic Circular Dichroism (XMCD)</li></ul>



Silicon Drift Detectors

Micro-Channel Plate w/  
Resistive Anode Encoder



Polarization Analyzer

Filter/Slit Wheel w/  
Photodiode and CEM